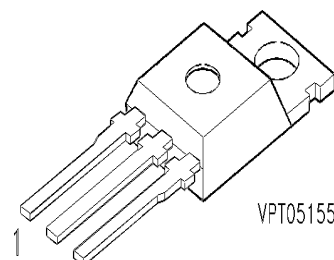


SIPMOS® Power Transistor

- N-Channel
- Enhancement mode
- Avalanche rated
- dv/dt rated
- 175°C operating temperature



Pin 1	Pin 2	Pin 3
G	D	S

Type	V_{DS}	I_D	$R_{DS(on)}$	@ V_{GS}	Package	Ordering Code
SPPXXN10	100 V	52 A	0.033 Ω	$V_{GS} = 10$ V	P-TO220-3-1	-
-					-	-

Maximum Ratings, at $T_j = 25$ °C, unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current $T_C = 25$ °C $T_C = 100$ °C	I_D	52 36	A
Pulsed drain current $T_C = 25$ °C	I_{Dpulse}	208	
Avalanche energy, single pulse $I_D = 52$ A, $V_{DD} = 25$ V, $R_{GS} = 25$ Ω	E_{AS}	650	mJ
Avalanche current, periodic limited by T_{jmax}	I_{AR}	52	A
Avalanche energy, periodic limited by $T_{j(max)}$	E_{AR}	17.5	mJ
Reverse diode dv/dt $I_S = 52$ A, $V_{DD} \leq V_{(BR)DSS}$, $di/dt = 200$ A/ μ s, $T_{jmax} = 175$ °C	dv/dt	6	kV/ μ s
Gate source voltage	V_{GS}	± 20	V
Power dissipation $T_C = 25$ °C	P_{tot}	175	W
Operating temperature	T_j	-55 ... +175	°C
Storage temperature	T_{stg}	-55 ... +175	
IEC climatic category; DIN IEC 68-1		55/175/56	

Electrical Characteristics

Parameter at $T_j = 25\text{ °C}$, unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	

Thermal Characteristics

Thermal resistance, junction - case	R_{thJC}	-	tbd	0.85	K/W
Thermal resistance, junction - ambient	R_{thJA}	-	62.5	-	
SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ¹⁾	R_{thJA}	- -	tbd tbd	- -	

Static Characteristics

Drain- source breakdown voltage $V_{GS} = 0\text{ V}$, $I_D = 0.25\text{ mA}$	$V_{(BR)DSS}$	100	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 0.75\text{ mA}$	$V_{GS(th)}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 50\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 25\text{ °C}$ $V_{DS} = 50\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 150\text{ °C}$	I_{DSS}	- -	0.1 -	1 100	μA
Gate-source leakage current $V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$	I_{GSS}	-	10	100	
Drain-Source on-state resistance $V_{GS} = 10\text{ V}$, $I_D = 36\text{ A}$	$R_{DS(on)}$	-	-	0.033	Ω

¹ Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6 cm² (one layer, 70μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics

Parameter at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	
Dynamic Characteristics					
Transconductance $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(ON)max}$, $I_D = 36\text{ A}$	g_{fs}	tbd	-	-	S
Input capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{iss}	-	-	tbd	pF
Output capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{oss}	-	-	tbd	
Reverse transfer capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{rss}	-	-	tbd	
Turn-on delay time $V_{DD} = 30\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 52\text{ A}$, $R_G = 4.7\text{ }\Omega$	$t_{d(ON)}$	-	-	tbd	ns
Rise time $V_{DD} = 30\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 52\text{ A}$, $R_G = 4.7\text{ }\Omega$	t_r	-	-	tbd	
Turn-off delay time $V_{DD} = 30\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 52\text{ A}$, $R_G = 4.7\text{ }\Omega$	$t_{d(OFF)}$	-	-	tbd	
Fall time $V_{DD} = 30\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 52\text{ A}$, $R_G = 4.7\text{ }\Omega$	t_f	-	-	tbd	

Electrical Characteristics

Parameter at $T_j = 25\text{ °C}$, unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

Gate charge at threshold $V_{DD} = 0\text{ V}$, $I_D \geq 0,1\text{ A}$, $V_{GS} = 0\text{ to }1\text{ V}$	$Q_{G(th)}$	-	tbd	-	nC
Gate charge at $V_{gs}=7\text{ V}$ $V_{DD} = 24\text{ V}$, $I_D = 52\text{ A}$, $V_{GS} = 0\text{ to }7\text{ V}$	$Q_{g(7)}$	-	tbd	-	nC
Gate charge total $V_{DD} = 80\text{ V}$, $I_D = 52\text{ A}$, $V_{GS} = 0\text{ to }10\text{ V}$	Q_g	-	tbd	-	
Gate plateau voltage $V_{DD} = -\text{ V}$, $I_D = 52\text{ A}$	$V_{(plateau)}$	-	tbd	-	V

Reverse Diode

Inverse diode continuous forward current $T_C = 25\text{ °C}$	I_S	-	-	52	A
Inverse diode direct current,pulsed $T_C = 25\text{ °C}$	I_{SM}	-	-	208	
Inverse diode forward voltage $V_{GS} = 0\text{ V}$, $I_F = 104\text{ A}$	V_{SD}	-	tbd	-	V
Reverse recovery time $V_R = 80\text{ V}$, $I_F = I_S$, $di_F/dt = 100\text{ A}/\mu\text{s}$	t_{rr}	-	-	tbd	ns
Reverse recovery charge $V_R = 80\text{ V}$, $I_F = I_S$, $di_F/dt = 100\text{ A}/\mu\text{s}$	Q_{rr}	-	-	tbd	μC

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